

Material Reconstruction in EPMA as a Bayesian Inverse Problem

Lunch Talk, ACoM

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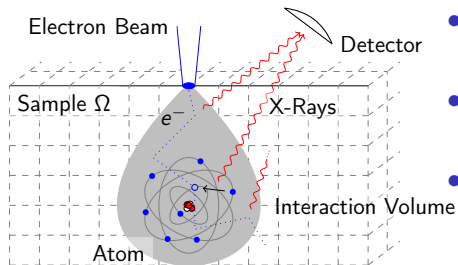
Was once:

Final Project - Stochastic Numerics SS2019

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- electron beam ionizes atoms
- relaxation by emission of characteristic x ray
- intensity of x-rays (k-ratios) measured by detector

Inverse Problem

→ given measured k-ratios \mathbf{k}^{exp} (normalized x-ray intensities)

What is the chemical composition \mathbf{c} that caused those measurements?

- ① Problem Setting
- ② Solution of the Inverse Problem
- ③ Forward Model
- ④ Sources of Uncertainty
- ⑤ Sampling-Algorithm: Metropolis-Hastings
- ⑥ Results and Convergence Diagnostics

Bayesian Inversion - Solution of the Inverse Problem

Classical approach: numerical optimization

- define a forward model $\mathbf{k}(\mathbf{c})$
- define a cost function $J(\mathbf{c}) = \|\mathbf{k}^{\text{exp}} - \mathbf{k}^{\text{mod}}(\mathbf{c})\|^2$
- numerical optimization (gradient, regularization, data filtering, ...)

Bayesian Inversion

- treat \mathbf{c} as a random variable (random field)
- prior information: $\pi(\mathbf{c})$
- likelihood: $\pi(\mathbf{k}^{\text{obs}}|\mathbf{c})$ (forward model)

Given \mathbf{k}^{obs} , what do we know about \mathbf{c} ?

Given \mathbf{k}^{obs} , what do we know about \mathbf{c} ?

$$\text{joint probability } \pi(\mathbf{c}|\mathbf{k}^{obs})\pi(\mathbf{k}^{obs}) = \pi(\mathbf{c}, \mathbf{k}^{obs}) = \pi(\mathbf{k}^{obs}|\mathbf{c})\pi(\mathbf{c})$$

Bayes' Theorem

$$\underbrace{\pi(\mathbf{c}|\mathbf{k}^{obs})}_{\text{posterior}} \propto \underbrace{\pi(\mathbf{k}^{obs}|\mathbf{c})}_{\text{likelihood}} \underbrace{\pi(\mathbf{c})}_{\text{prior}}$$

- the posterior is the 'solution' to the inverse problem

using $\pi(\mathbf{c}|\mathbf{k}^{obs})$ we can compute:

- expected value of mass fractions $\mathbb{E}(\mathbf{c}|\mathbf{k}^{obs})$
- maximum a posteriori (MAP) estimate (maximum likelihood)
- confidence intervals of the estimates

utilizing Monte Carlo methods (here Metropolis-Hastings)

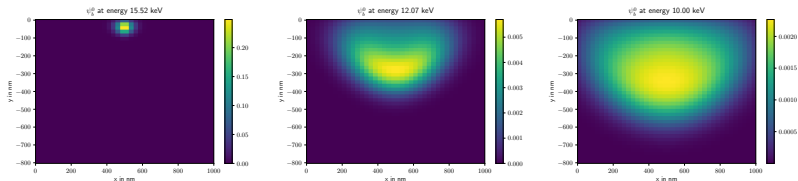
Electron Transport - $\mathcal{M}1$ -Model

- given: chemical composition $\mathbf{c}(x)$
- solve: $\mathcal{M}1$ -Model (Linear Boltzmann, continuously-slowing-down approximation, moment expansion, minimum entropy closure)

$$\partial_\epsilon \left(S(\mathbf{c}, \epsilon) \begin{pmatrix} \psi_b^0(x, \epsilon) \\ \psi_b^1(x, \epsilon) \end{pmatrix} \right) + \nabla_x \begin{pmatrix} \psi_b^1(x, \epsilon) \\ \psi_{ME}^2(\psi_b^0, \psi_b^1) \end{pmatrix} + \begin{pmatrix} 0 & 0 \\ 0 & T(\mathbf{c}, \epsilon)I \end{pmatrix} \begin{pmatrix} \psi_b^0(x, \epsilon) \\ \psi_b^1(x, \epsilon) \end{pmatrix} = 0$$

- boundary conditions capture the electron beam
- we use: finite volume method (library: CLAWPACK)

Example: Electron Probe Microanalysis



X Ray Intensities

- calculate: k-ratios

$$k_{bi} = \frac{1}{I_{std}^i} \int_{\Omega} \int_{\epsilon_{min}}^{\epsilon_{max}} e^{-\int_{d(x)} \mu^i(\mathbf{c}) dy} \omega^i \sigma_{ion}^i(\epsilon) N^i(\mathbf{c}) \psi_b^0(\mathbf{c}, \mathbf{x}, \epsilon) d\epsilon d\mathbf{x}$$

here we consider: ionization, fluorescence, absorption, ...

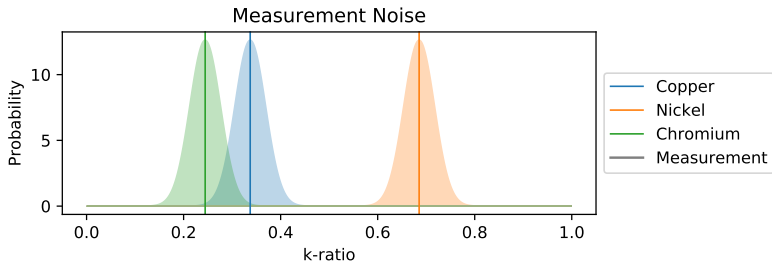
Uncertainty in

- model (e.g. parameter, simplification)
- experimental setup
- ...

assume (academic):

- no model uncertainty
- independent gaussian noise (detector: Poisson point process)

$$\mathbf{k}^{\text{exp}} - \mathbf{k}^{\text{mod}}(\mathbf{c}) \sim N(0, \text{diag}(\sigma^2, \dots))$$



→ likelihood $\pi(\mathbf{k}^{\text{exp}}|\mathbf{c})$

Prior information

$$0 \leq \mathbf{c}_{ik} \leq 1 \quad \forall \begin{matrix} i=1,\dots,n_c \\ k=1,\dots,n_e \end{matrix}$$

$$\sum_{k=1}^{n_e} \mathbf{c}_{ik} = 1 \quad \forall i=1,\dots,n_c$$

Dirichlet Distribution

$$X \sim \text{Dir}(\alpha) \quad \alpha \in \mathbb{R}^n$$

- pdf: $\frac{1}{B(\alpha)} \prod_{i=1}^n x_i^{\alpha_i-1}$
- normalizing constant $B(\alpha)$
- $\mathbb{E}[X_j] = \frac{\alpha_j}{\alpha_o}$
- $\text{Var}[X_j] = \frac{\alpha_j}{\alpha_o} \frac{1 - \frac{\alpha_j}{\alpha_o}}{\alpha_o + 1}$
- $\alpha_o = \sum_{i=1}^n \alpha_i$

- in each subdomain $\mathbf{c}_i: \sim \text{Dir}(\alpha_i)$ independent
- we use $\alpha_i = [1, 1, \dots] \forall i$
- uniform over the support

→ prior $\pi(\mathbf{c})$

Bayes' Theorem

$$\underbrace{\pi(\mathbf{c}|\mathbf{k}^{obs})}_{\text{posterior}} \propto \underbrace{\pi(\mathbf{k}^{obs}|\mathbf{c})}_{\text{likelihood}} \underbrace{\pi(\mathbf{c})}_{\text{prior}}$$

Metropolis Hastings: Idea

- construct a Markov Chain (stationary distribution = desired distribution)
- propose a sample (based on the current sample)
- accept / reject the sample (probability based on detailed balance)

Sampling algorithm: Metropolis-Hastings

Algorithm 1: Metropolis-Hastings: to sample from $\pi(\mathbf{c}|\mathbf{k})$

```
1 Initialize  $\mathbf{c}^{(0)} \sim \text{prior}$ 
2 for  $j = 1, 2, \dots$  do
3   Propose:  $\mathbf{c}^* \sim q(\cdot|\mathbf{c}^{(j-1)})$ 
4   Acceptance Probability:
      
$$A(\mathbf{c}^*|\mathbf{c}^{(j-1)}) = \min\left(1, \frac{q(\mathbf{c}^{(j-1)}|\mathbf{c}^*)\pi(\mathbf{c}^*|\mathbf{k}^{obs})}{q(\mathbf{c}^*|\mathbf{c}^{(j-1)})\pi(\mathbf{c}^{(j-1)}|\mathbf{k}^{obs})}\right)$$

5    $u \sim \text{Uni}([0, 1])$ 
6   if  $u < A$  then
7     | Accept:  $\mathbf{c}^{(j)} = \mathbf{c}^*$ 
8   else
9     | Reject:  $\mathbf{c}^{(j)} = \mathbf{c}^{(j-1)}$ 
```

-
- How should we choose the proposal $q(\cdot|\mathbf{c}^{(i-1)})$?

Metropolis-Hastings: Proposal distribution $q(\cdot | \mathbf{c}^{(j-1)})$

Often: $\mathcal{N}(\mathbf{c}^{(j-1)}, \Sigma_p)$ as proposal distribution

- with $\mathbf{c}^{(j-1)}$ as the mean and a chosen covariance Σ_p
- Not applicable here (conditions on \mathbf{c})

→ Use a proposal distribution which (hopefully) is similar to the posterior

Idea: Use Dirichlet again

In each subdomain i : $\mathbf{c}_i^* \sim q(\cdot, \mathbf{c}^{(j-1)}) = \text{Dir}(r\mathbf{c}_i^{(j-1)}) \quad r \in \mathbb{R}$

- $\mathbb{E}[\mathbf{c}_i^*] = \mathbf{c}_i^{(j-1)}$
- $\text{Var}[\mathbf{c}_{ik}^*] = \frac{\mathbf{c}_{ik}^{(j-1)}(1-\mathbf{c}_{ik}^{(j-1)})}{r+1}$
- We can control the variance of the proposal with r

Physical Domain

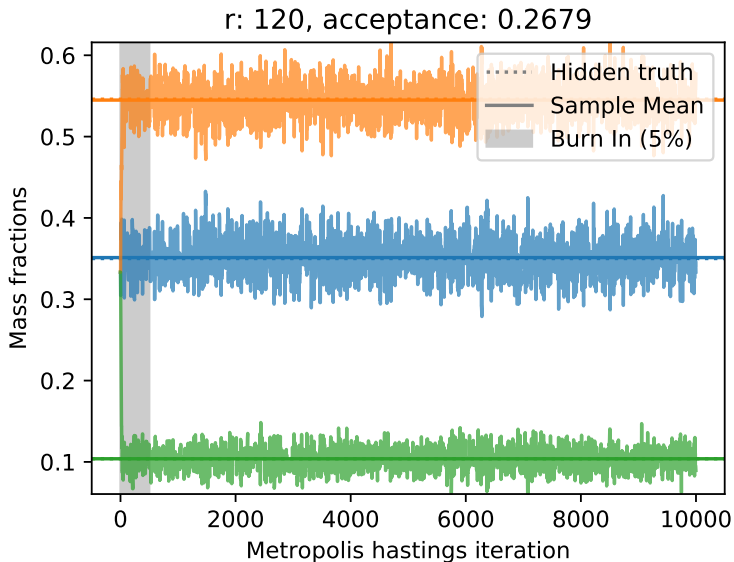
Number of subdomains	1
Number of chemical elements	3

Numerical parameters

Spatial Grid \bar{x}	40×40 , (1000 \times 800nm)
Number of steps ϵ	100, ([10, 17] keV)
Beam energy ϵ_{beam}	16 kV
Measurement noise σ^2	0.001

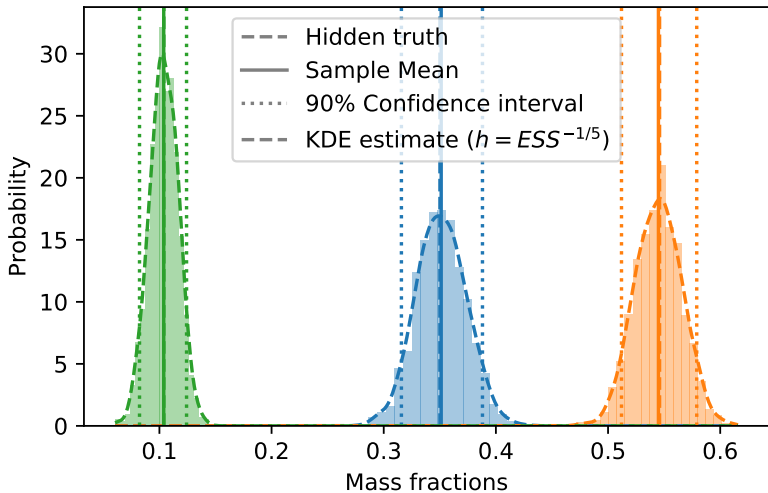
For the first try, we choose:

Number of MCMC iterations	10000
Proposal variance r	120
Initial mass fraction $c^{(0)}$	[0.33, 0.33, 0.33]



Results: Histogram / KDE / Confidence Intervals

r: 120, acceptance: 0.2679



Autocorrelation at lag k

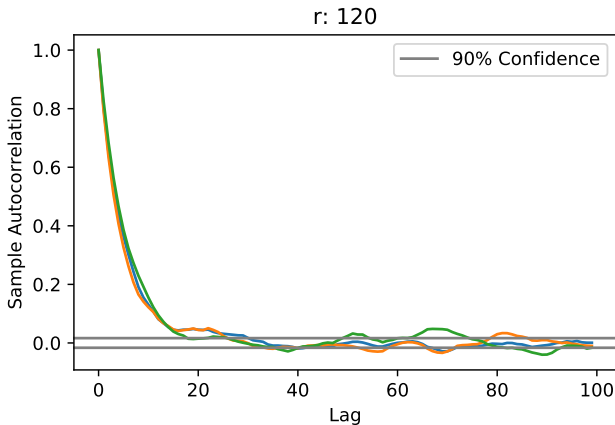
- Correlation of the signal with itself at lag k .

$$\hat{\rho}(k) = \frac{\sum_{i=1}^{T-k} (x_{i+k} - \bar{x})(x_i - \bar{x})}{\sum_{i=1}^T (x_i - \bar{x})^2}, \quad \bar{x} = \sum_{i=1}^T \frac{x_i}{T}$$

Effective Sample Size

- ESS describes the number of weakly correlated samples.
- $ESS = \frac{N}{1 + 2 \sum_{k=1}^{\infty} \rho(k)}$, with N number of samples and $\rho(k)$ the correlation at lag k
- Best expectation: $\frac{ESS}{N}$ close to 1.

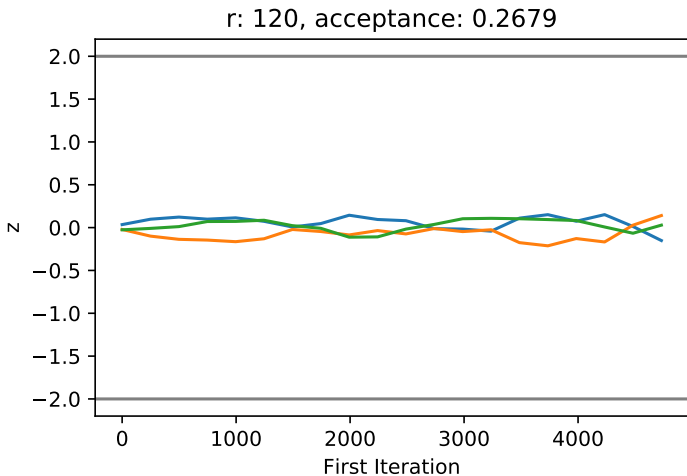
Diagnostics: Autocorrelation and ESS



For $r = 120$, $N = 10000$: $ESS = \min [737.6, 732.4, 660.2] = 660$

Geweke test

- **Idea** A converged chain has the same expectation in the first and last part
- Say T_1 corresponds to the first 10% of the samples and T_2 to the last 50%
- $z = \frac{\mathbb{E}[T_1] - \mathbb{E}[T_2]}{\sqrt{\text{Var} T_1 + \text{Var} T_2}}$ should converge to normal distribution

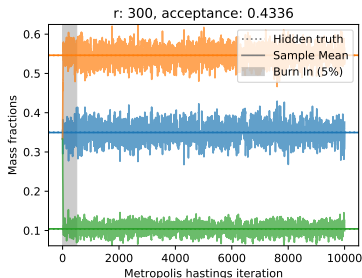
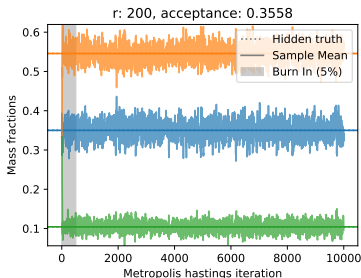
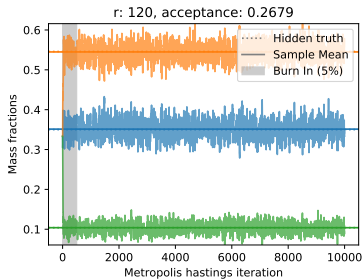
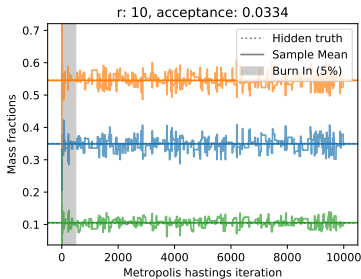


Gelman-Rubin Convergence Diagnostic

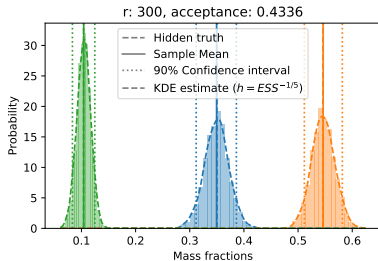
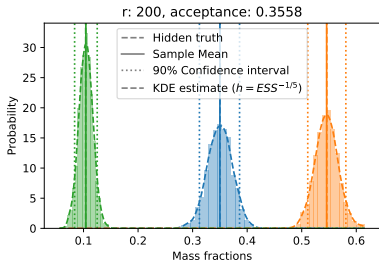
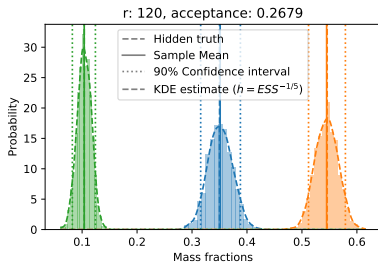
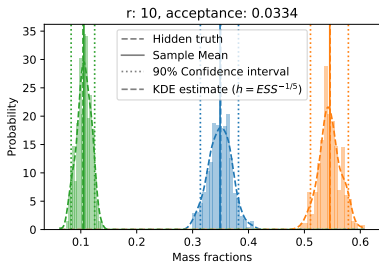
- Evaluate MCMC convergence by comparing estimated between-chain and within-chain variance for each parameter
- $\mathbf{c}_m^{(j)}$ with $m = 1 \dots M$ different chains and $j = 1 \dots N$ samples
- $\hat{\mathbf{c}}_m$ sample mean and $\hat{\sigma}_m^2$ sample variance
- Overall mean $\hat{\mathbf{c}} = \frac{1}{M} \sum_{m=1}^M \hat{\mathbf{c}}_m$
- Between-chain variance $B = \frac{N}{M-1} \sum_{m=1}^M (\hat{\mathbf{c}}_m - \hat{\mathbf{c}})^2$
- Within-chain variance $W = \frac{1}{M} \sum_{m=1}^M \hat{\sigma}_m^2$
- Pooled variance $\hat{V} = \frac{N-1}{N} W + \frac{M+1}{MN} B$
- Test: if $\frac{\hat{V}}{W}$ is close to one, the chains have converged

Parameter study (different variances of the proposal r)

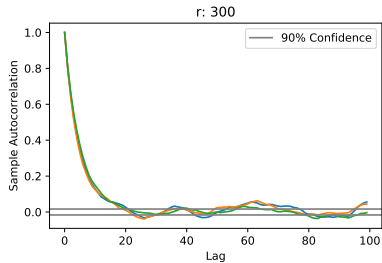
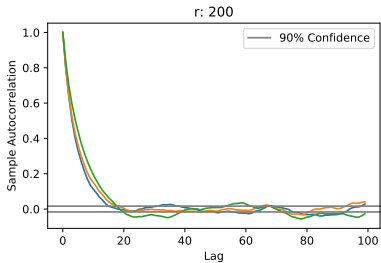
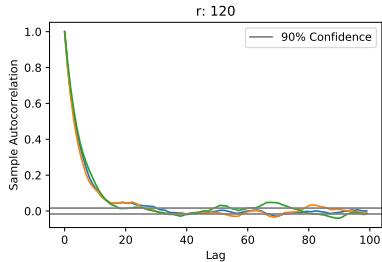
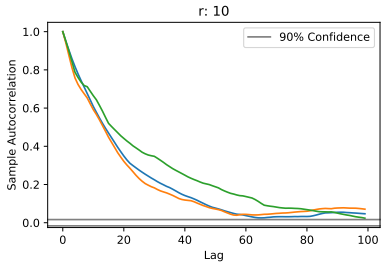
Trace Plots: Impact of r



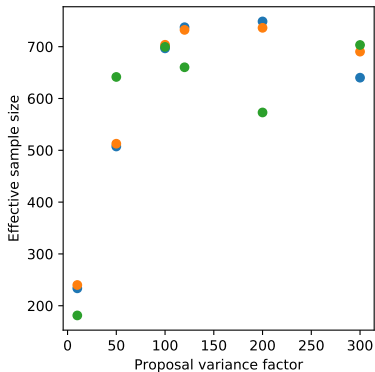
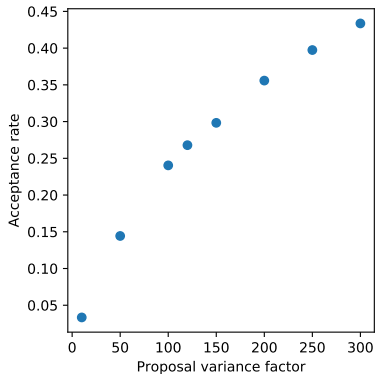
Histogram/KDE: Impact of r



Autocorrelation: Impact of r

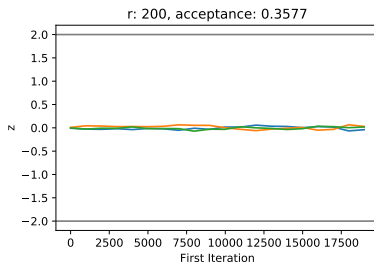
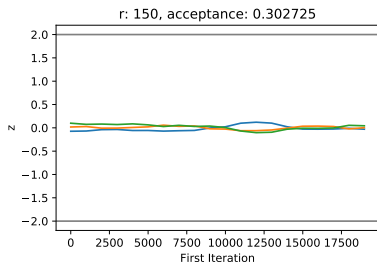
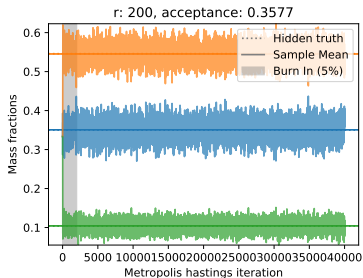
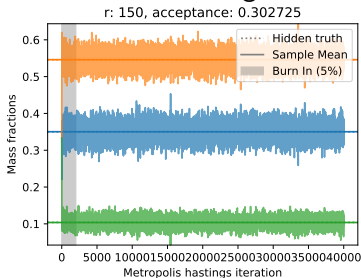


Acceptance rate and ESS

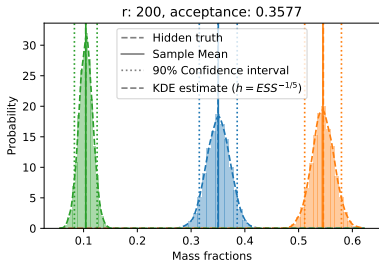
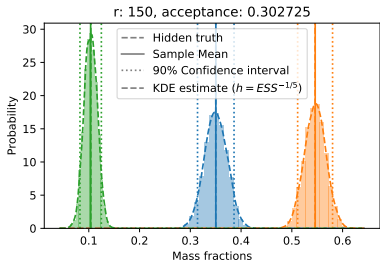
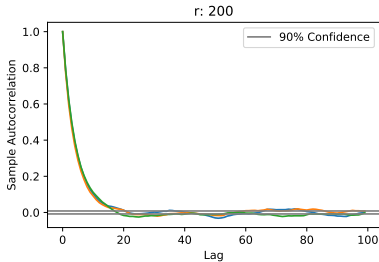
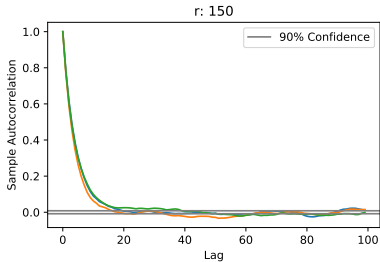


More numerical experiments

→ run the chain longer: $N = 40000$?

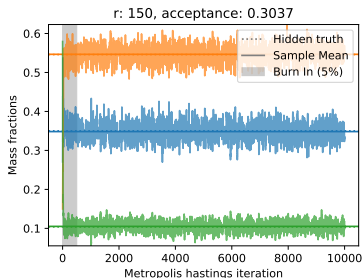
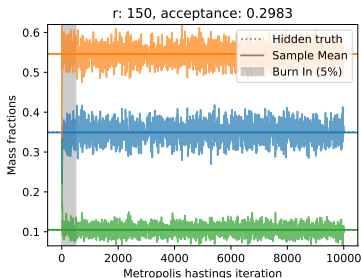
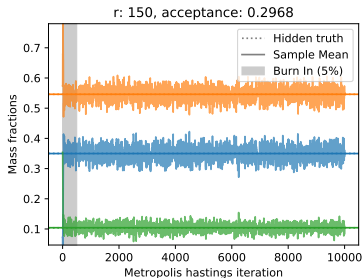
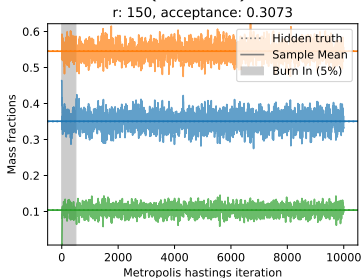


More numerical experiments



More numerical experiments

→ run with ($M = 6$) different initial conditions $r = 150$ $N = 10000$



Apply the Gelman-Rubin Diagnostic: $M = 6$, $N = 10000$, $r = 150$
for the three mass fractions (parameters) we get

- \mathbf{c}_0 : $\frac{\hat{V}}{W} = 1.0026$
- \mathbf{c}_1 : $\frac{\hat{V}}{W} = 1.0006$
- \mathbf{c}_2 : $\frac{\hat{V}}{W} = 1.0029$

Conclusion

- simple integration with existing forward models (no gradient information)
- uncertainties of the reconstruction result
- no convergence guarantee (run the chain forever)

Further Investigation

- more subdomains (\rightarrow more parameters, but more realistic)
- parameter tuning for r
- more realistic likelihood (include model uncertainties, other measurement errors)
- more sophisticated proposal distribution



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